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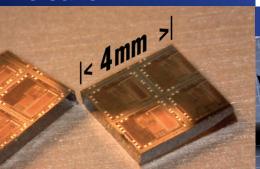
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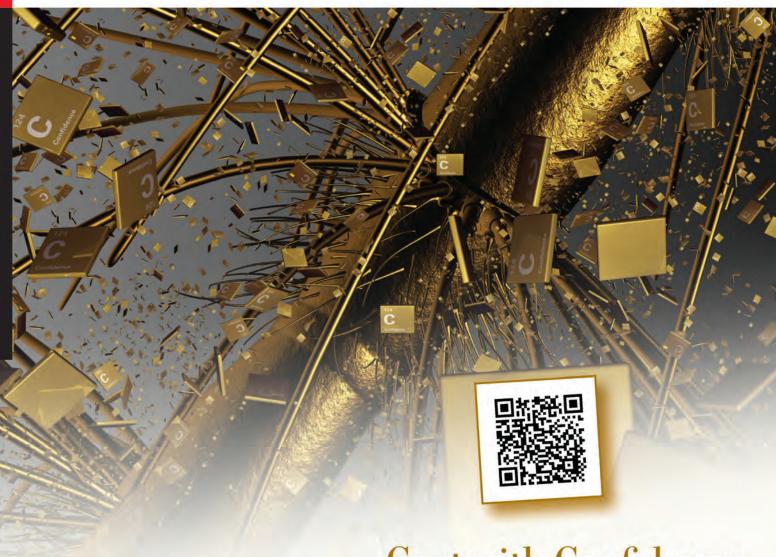
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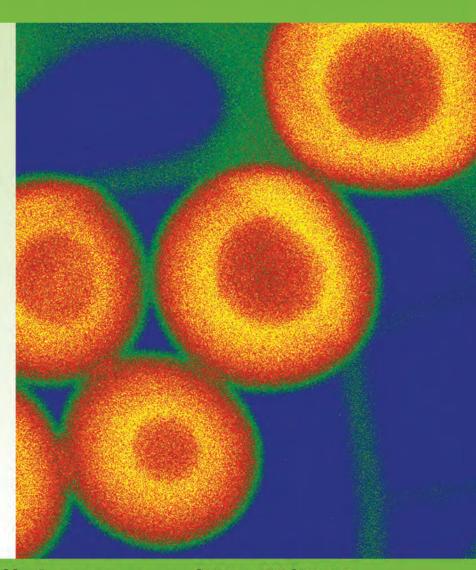
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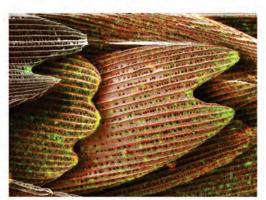


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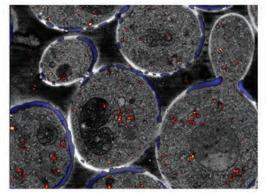
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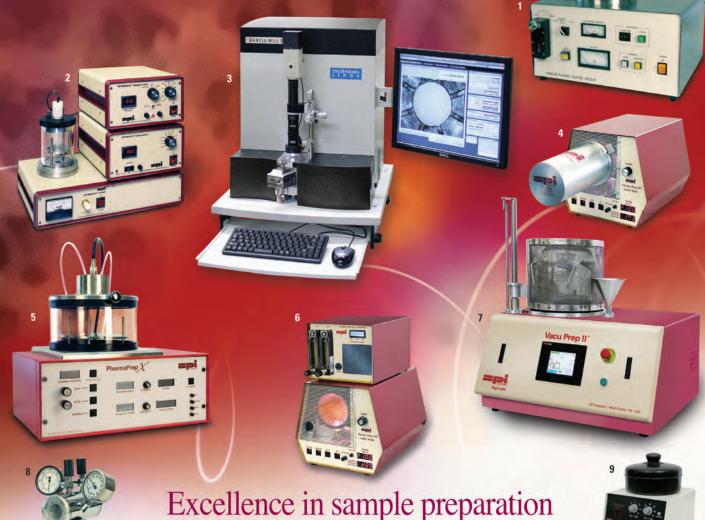


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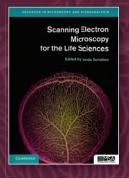
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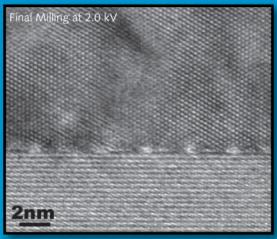
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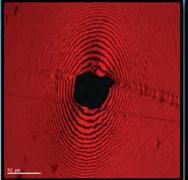
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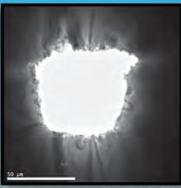
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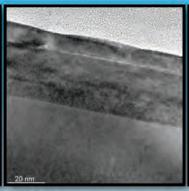


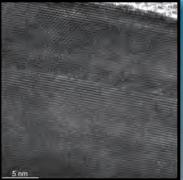












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Bottom images: Images at Increasing magnification, all stored in Gatan Digital Micrograph", left from PIPS" || optical camera, others from Gatan Ones SC2008 camera on TEM, at 200 kV. SrRuO/SninPZT/SrRuO, thin film on SrTiO, (001) with PIPS" || final polishing step at 300 Volts.

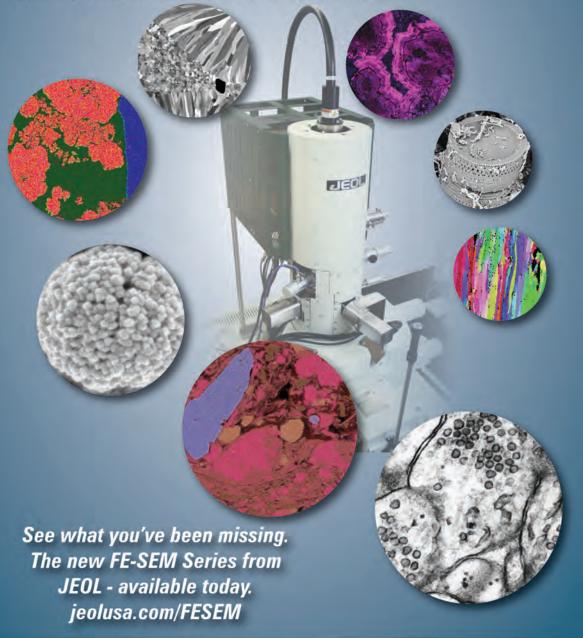




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